

ABSTRACT

5 Provided is a substrate with a thin film comprising a thin film having excellent chemical resistance. A substrate with a thin film comprises a thin film on at least one of two main surfaces of the substrate. The thin film comprises chromium. When a diffracted X-ray intensity with respect to a diffraction angle 2θ is measured by an X-ray diffraction method using a $\text{CuK}\alpha$ ray for the thin film, a peak is detected in a range where the diffraction angle 2θ is 56 degrees or more and 60 degrees or less.